	Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
91	BRS	4364	tuples	USPAT; US-PGPUB	2003/09/03 11:19		
92	BRS	161	tuple and sdf	USPAT; US-PGPUB	2003/09/03 11:19		
93	BRS	42	tuple and rise same fall and delay	USPAT; US-PGPUB	2003/09/03 11:33		
94	BRS	1	tuple and rise same fall and delay and hdl	USPAT; US-PGPUB; DERWENT; IBM_TDB	2003/09/03 11:33		
95	BRS	1	tuple and rise same fall and delay and hdl	USPAT; US-PGPUB	2003/09/03 12:10		
96	BRS	16	sdf same correlation	USPAT; US-PGPUB	2003/09/03 12:14		
97	BRS	16	sdf same correlation	USPAT; US-PGPUB; IBM_TDB	2003/09/03 12:14		
98	BRS	242	sdf and correlation	USPAT; US-PGPUB; IBM_TDB	2003/09/03 12:14		
99	BRS	7	sdf and correlation and rise same delay	USPAT; US-PGPUB; IBM_TDB	2003/09/03 12:15		
100	BRS	28	sdf and correlation and rise and fall and delay	USPAT; US-PGPUB; IBM_TDB	2003/09/03 12:17		
101	BRS	39	vhdl and correlation and rise and fall and delay	USPAT; US-PGPUB; IBM_TDB	2003/09/03 12:37		
127	BRS	16	vhdl and delay same value and tuple	USPAT; US-PGPUB	2003/09/05 09:20		
128	BRS	169	tuple and delay and (rise or fall) same time	USPAT; US-PGPUB	2003/09/05 09:20		
129	BRS	163	vhdl and delay same value and database	USPAT; US-PGPUB	2003/09/05 09:20		
130	BRS	171	tuple and delay and (rise or fall) same time	USPAT; US-PGPUB; DERWENT; IBM_TDB	2003/09/05 09:32		
131	BRS	130	tuple and delay and (rise or fall) same time and variable	USPAT; US-PGPUB; DERWENT; IBM_TDB	2003/09/05 09:32		
132	BRS	6	tuple and delay and (rise or fall) same time and variable and vhdl	USPAT; US-PGPUB; DERWENT; IBM_TDB	2003/09/05 09:42		
133	BRS	3	tuple and delay and (rise or fall) same time and variable and sdf	USPAT; US-PGPUB; DERWENT; IBM_TDB	2003/09/05 09:32		

	Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition
134	BRS	33	vital same compliant	USPAT; US-PGPUB; DERWENT; IBM_TDB	2003/09/05 09:43		
135	BRS	11	vital same compliant and delay	USPAT; US-PGPUB; DERWENT; IBM_TDB	2003/09/05 10:12		
136	BRS	6	vital same compliant and delay and sdf	USPAT; US-PGPUB; DERWENT; IBM_TDB	2003/09/05 14:44		
137	BRS	8	generic same parameter same interface and vhdl	USPAT; US-PGPUB; DERWENT; IBM_TDB	2003/09/05 14:47		
138	BRS	7	generic same parameter same interface and vhdl and timing	USPAT; US-PGPUB; DERWENT; IBM_TDB	2003/09/05 15:51		

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1 **Standardizing ASIC libraries in VHDL using VITAL: a tutorial**
Krolikoski, S.J.;
Custom Integrated Circuits Conference, 1995., Proceedings of the
IEEE 1995 , 1-4 May 1995
Page(s): 603 -610

[Abstract]   [PDF Full-Text (596 KB)] **IEEE CNF**

2 **VHDL sign-off simulation: what future?**
Bakowski, P.; Bouchard, F.; Caisso, J.-P.; Igier, F.;
VHDL International Users Forum. Spring Conference, 1994.
Proceedings of , 1-4 May 1994
Page(s): 136 -141

[Abstract]   [PDF Full-Text (356 KB)] **IEEE CNF**

3 **Deriving accurate ASIC cell fault models for VITAL compliant VHDL simulation**
Shaw, D.; Al-Khalili, D.; Rozon, C.;
Circuits and Systems, 2001. ISCAS 2001. The 2001 IEEE International
Symposium on , Volume: 5 , 6-9 May 2001
Page(s): 263 -266 vol. 5

[Abstract]   [PDF Full-Text (332 KB)] **IEEE CNF**

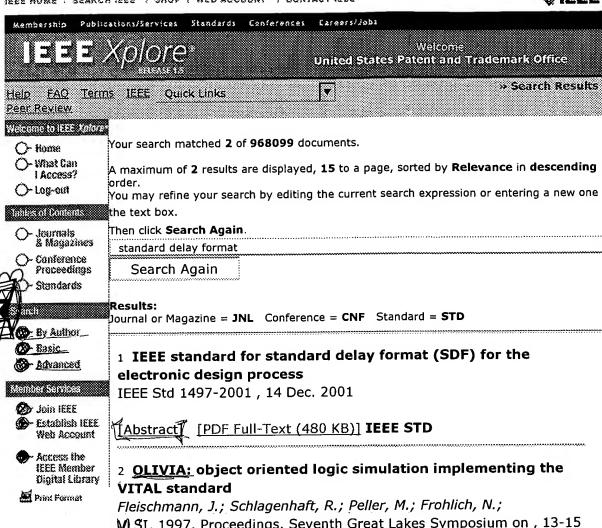4 **Aut mated defect to fault translati n for ASIC standard cell libraries**
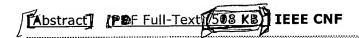*Shaw, D.; Al-Khalili, D.; Rozon, C.;*

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1 **IEEE standard for standard delay format (SDF) for the electronic design process**
IEEE Std 1497-2001 , 14 Dec. 2001

[Abstract]   [PDF Full-Text (480 KB)] **IEEE STD**

2 **OLIVIA: object oriented logic simulation implementing the VITAL standard**
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5 The work of breathing in a nonlinear model of respiratory mechanics

Athanasiades, A.; Ghorbel, F.; Clark, J.W., Jr.; Niranjan, S.C.; Liu, C.H.; Zwischenberger, J.B.; Bidani, A.;
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6 A SKILL^{TM}-based library for retargetable embedded analog cores

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[Abstract]   [PDF Full-Text (184 KB)] **IEEE CNF**

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